

Accelerating the development of thin film photovoltaic technologies: an Artificial Intelligence assisted methodology using spectroscopic and optoelectronic techniques.

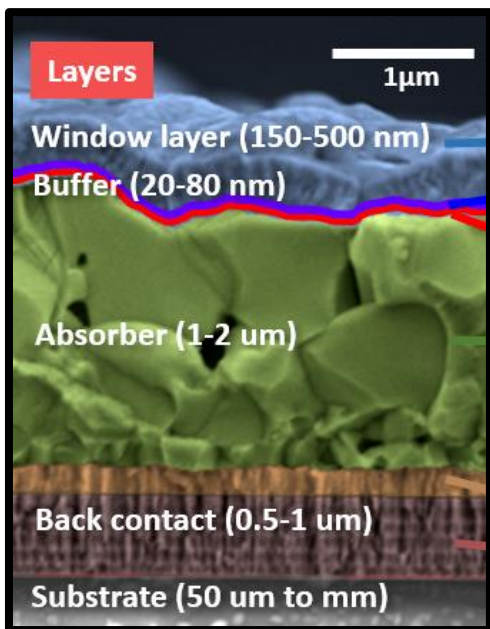
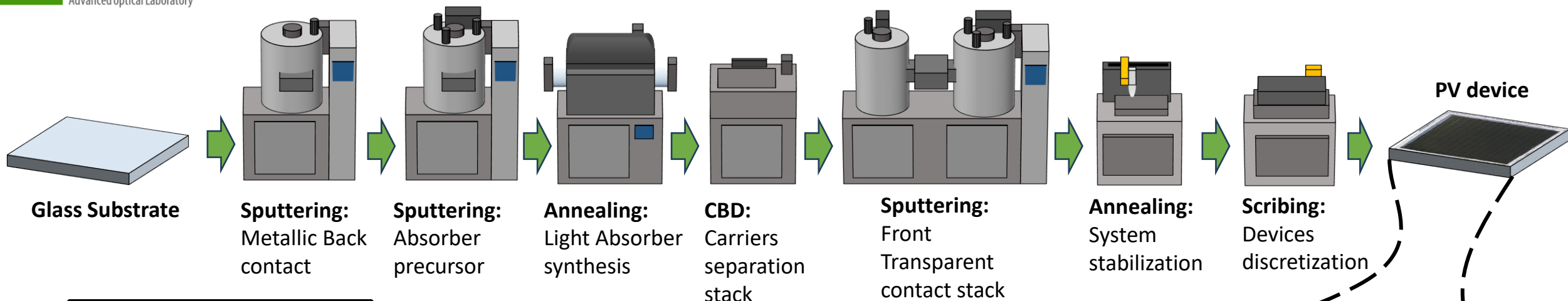
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Motivation: Complex fabrication of thin film PV devices fabrication (Kesterite case)



**Complex fabrication process involving:
7 processes with >100 controllable parameters**

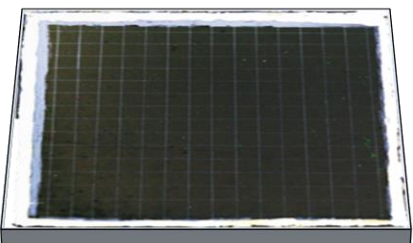
**Complex device (6 layers)
with strong interaction between them**

5x5 cm² sample
#196 3x3mm² Test-cell



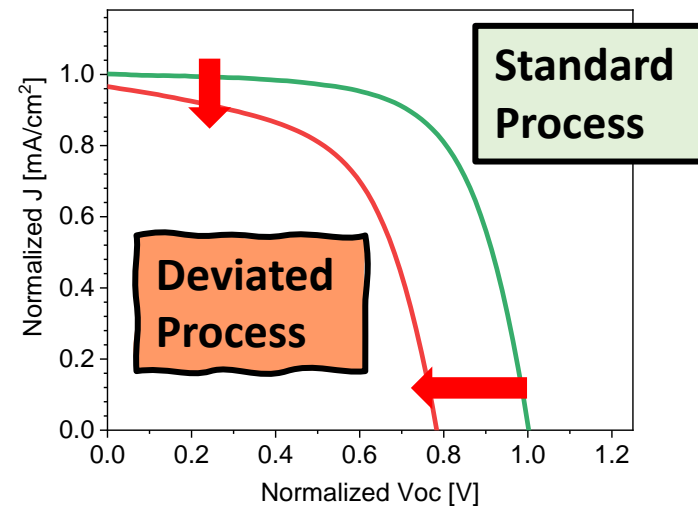
Back Contact terminal

The performance of PV devices is defined as...

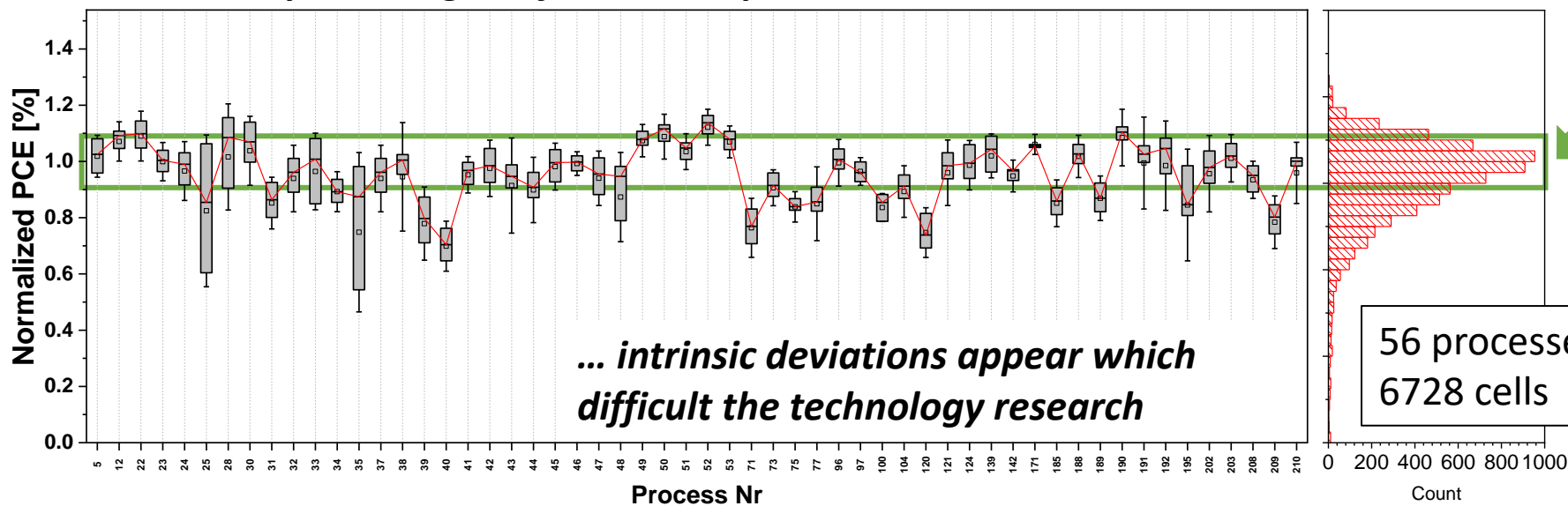


$$PCE = \frac{\text{Photogenerated power}}{\text{Irradiated power}}$$

$$PCE = \frac{J_{sc} \cdot V_{oc} \cdot FF}{\text{Light irradiation}}$$



When reproducing the fabrication process....



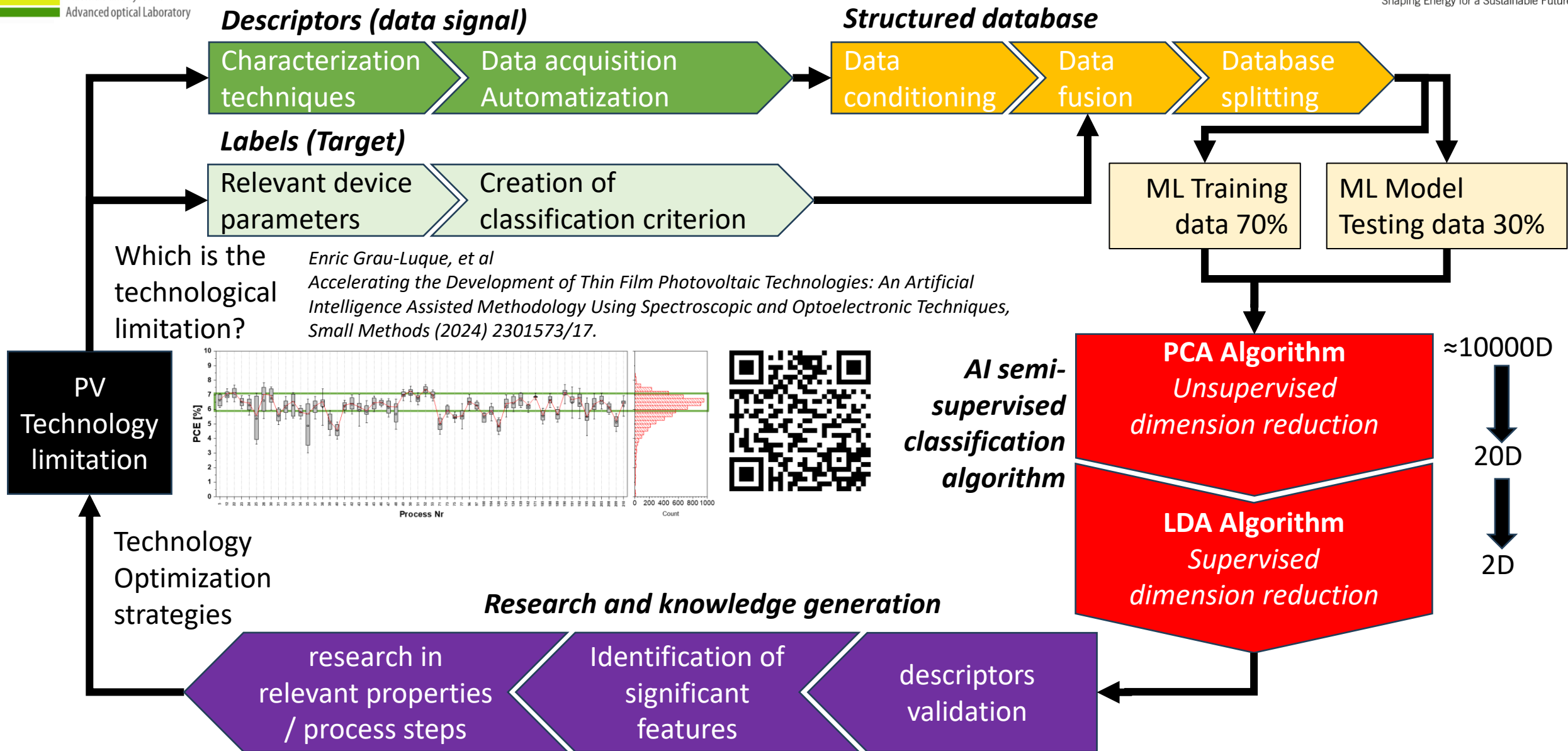
... intrinsic deviations appear which difficult the technology research

PCE: 0.9-1.1 → 48%
(10% deviation)

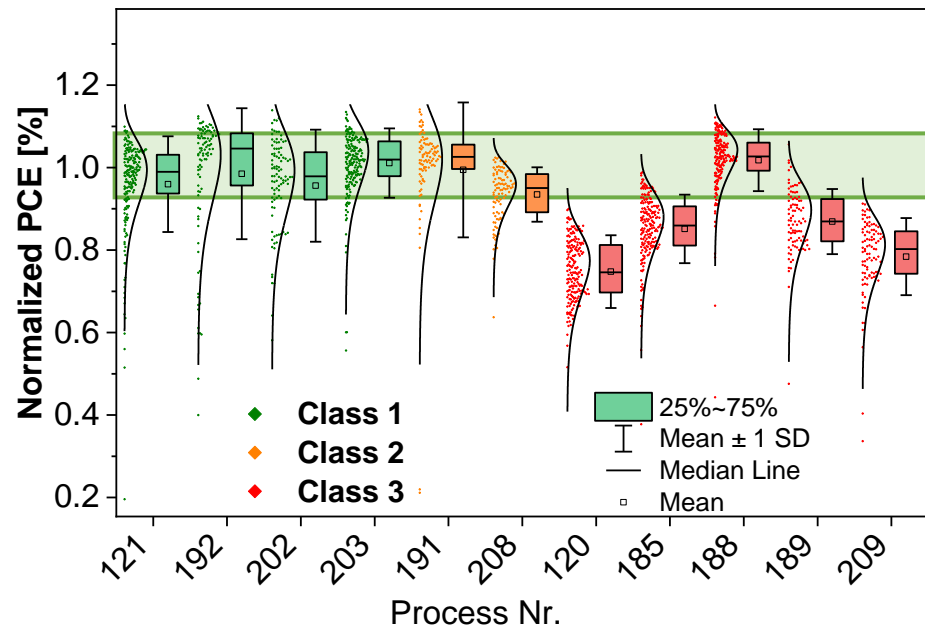
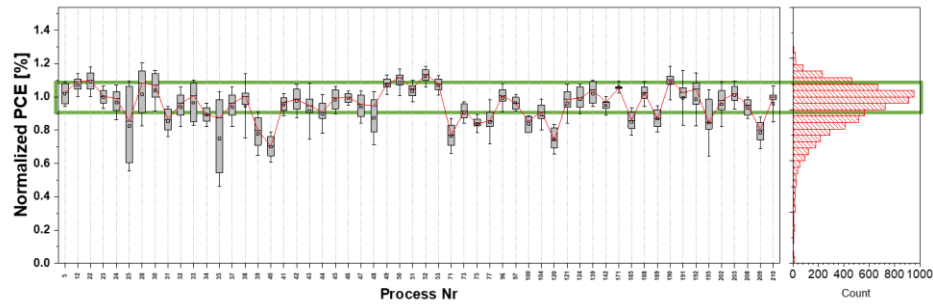
56 processes
6728 cells

QUESTION:
Which is the origin of the fluctuations?
Can we do something?

Methodology: workflow for the application of AI-assisted research

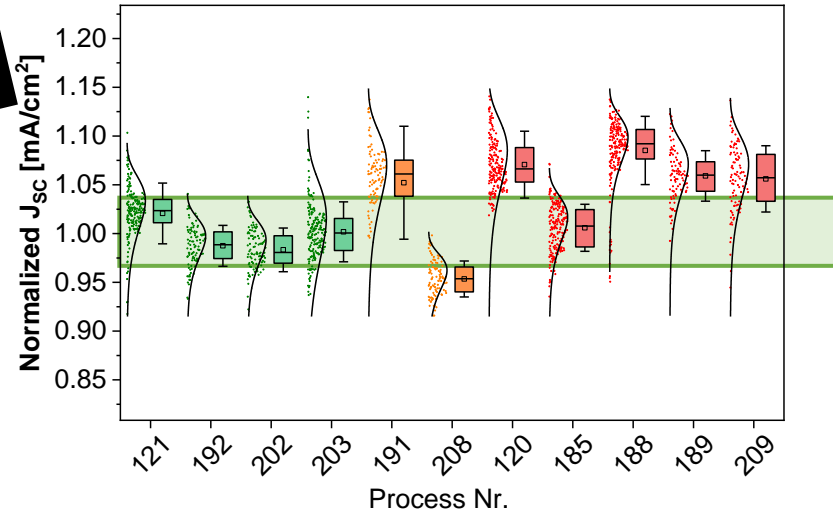
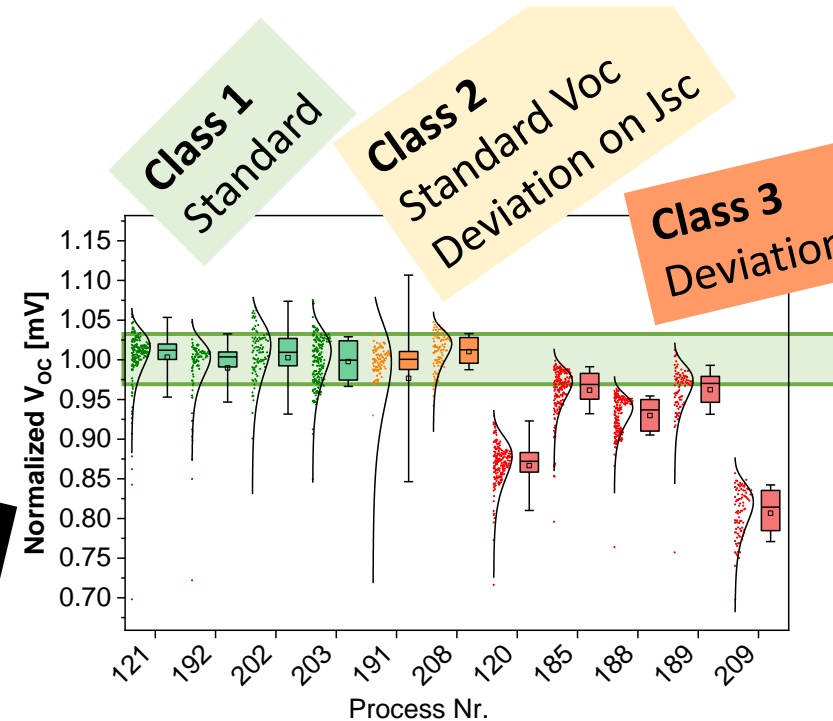
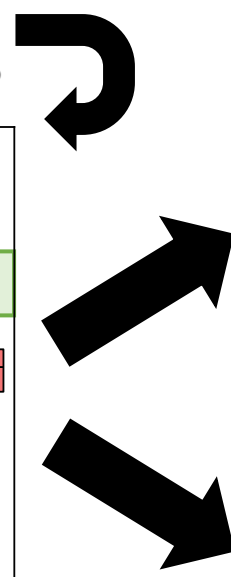


Labeling (classification criteria)



11 samples (≈ 2000 cells) have been selected:

- 4 with standard J_{sc} and V_{oc} values
- 7 with non-controlled process fluctuations



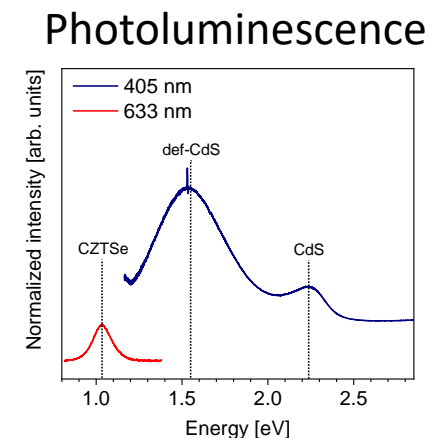
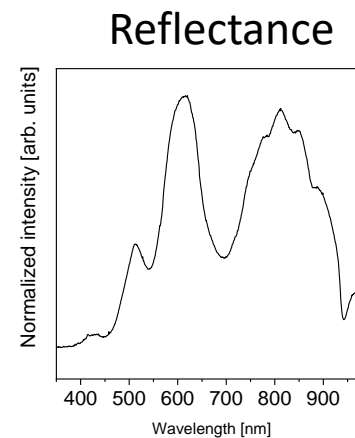
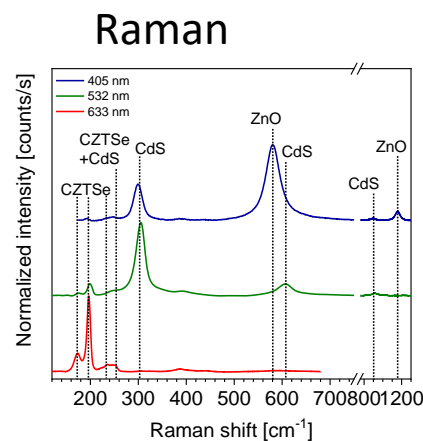
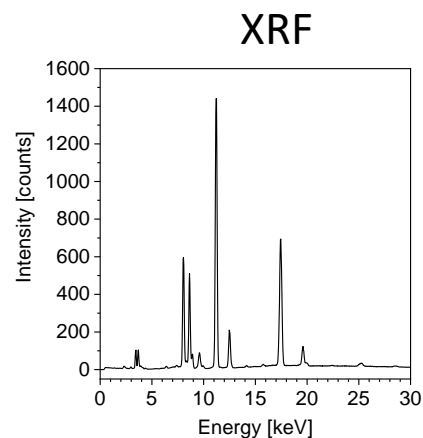
Definition of classification criteria

Characterization restrictions:

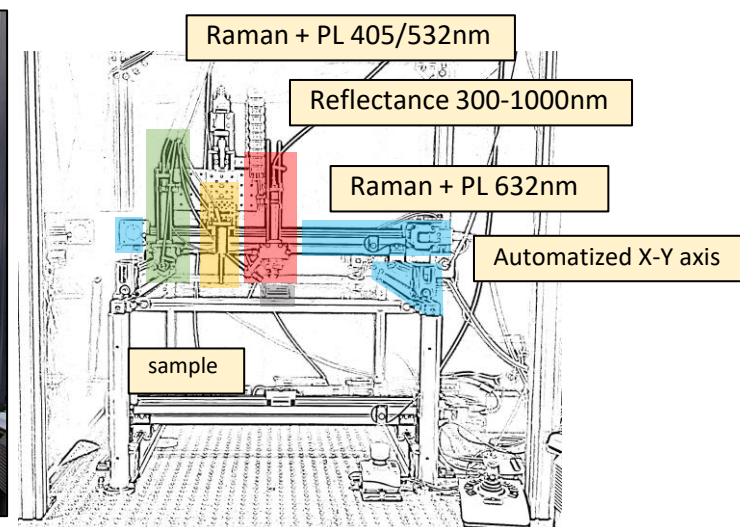
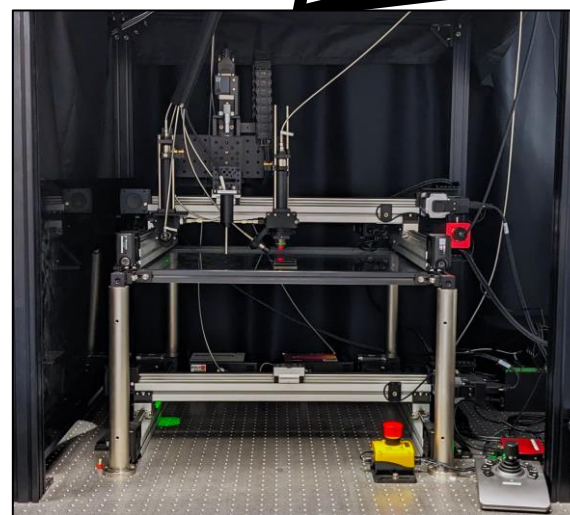
- Non-destructive
- No sample preparation required
- Fast acquisition (< 1min)
- Automatable (suitable for 'big data' acquisition)

Sensitive to changes on:

- Composition
- Thickness (nanoscale)
- Crystal structure and quality
- Secondary phases
- ...

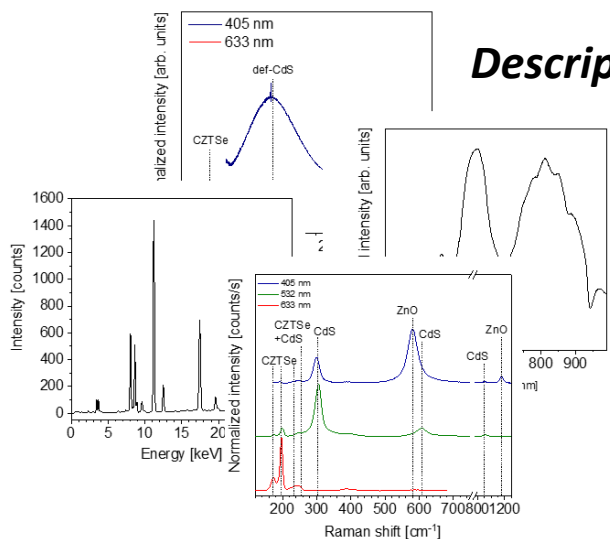


Do these descriptors provide information to describe the system?

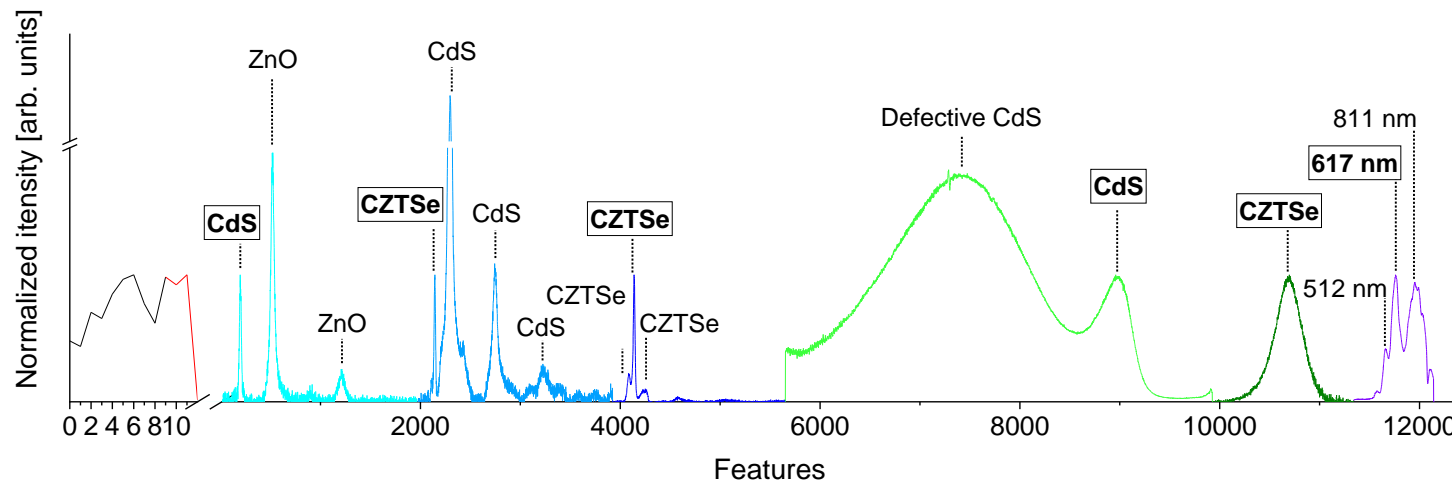
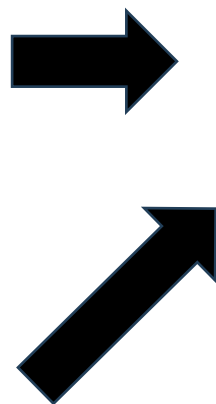


IREC developed combinational characterization platform

Structured database



Descriptors....



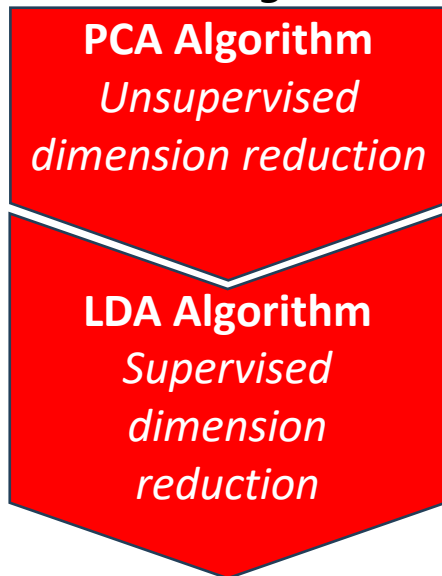
Labeling....

Class	Voc	Jsc
Class 1	Ok	Ok
Class 2	Ok	deviation
Class 3	Deviation	

Generation of a coherent dataset :

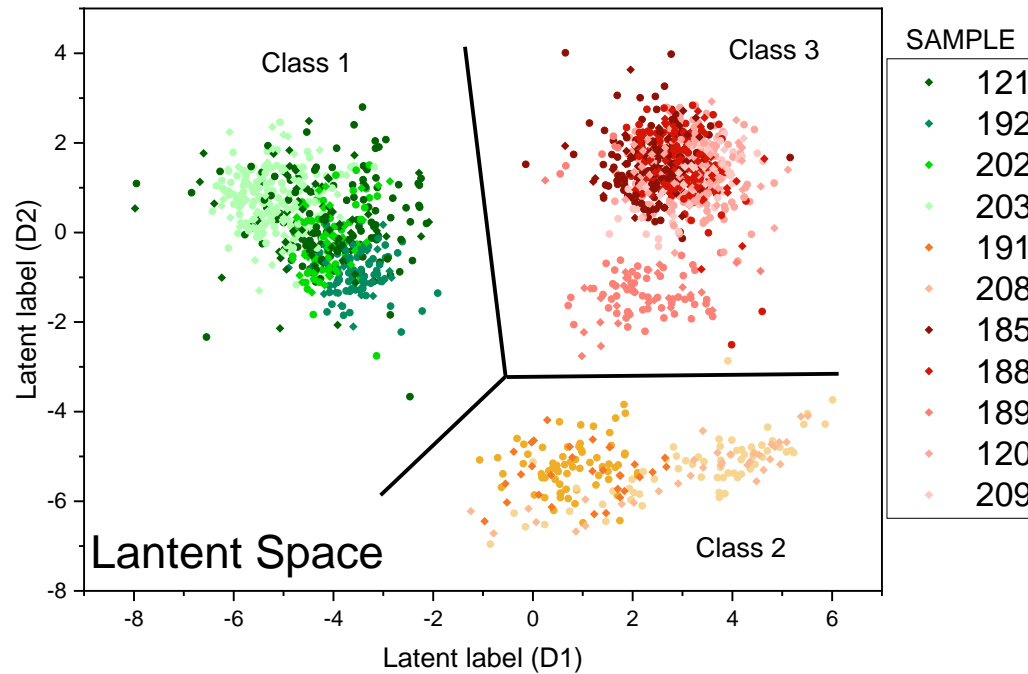
- >2000 data points
- >10000 descriptors from 4 characterization techniques per data point

AI semi-supervised classification algorithm

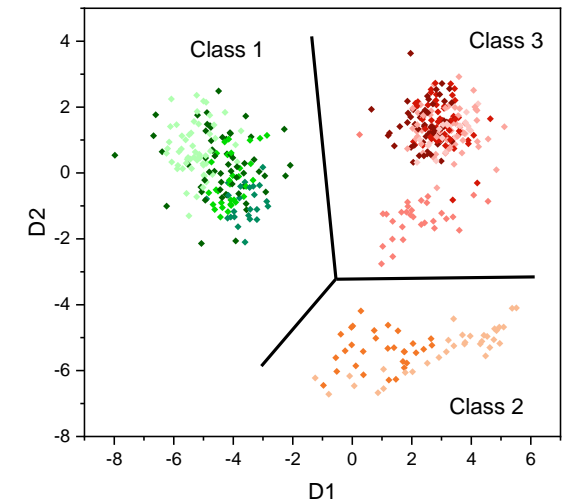


≈10000D
↓
20D
↓
2D

Training (70%) Score 99.82%



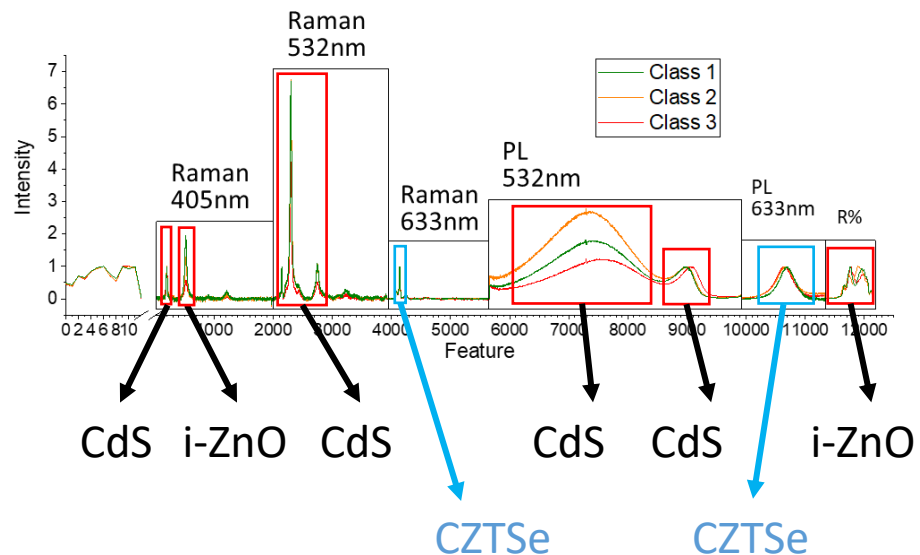
Test (30%) Score 98.93%



Latent space → good classification

- **Correlation between the descriptors** (characterization) and the **labeling** (optoelectronics)
- It's possible to **identify the origin of the deviations**

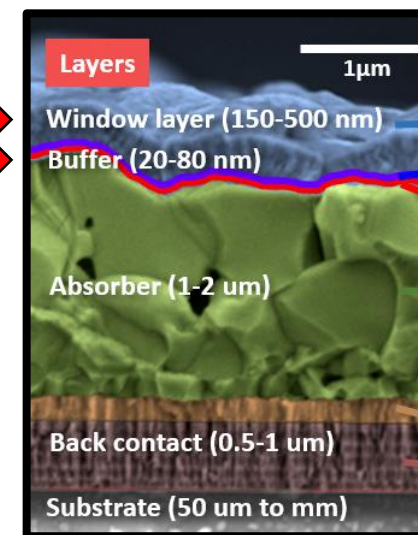
Merging the information



Automatic research:
Permits the identification of the fluctuation's origin

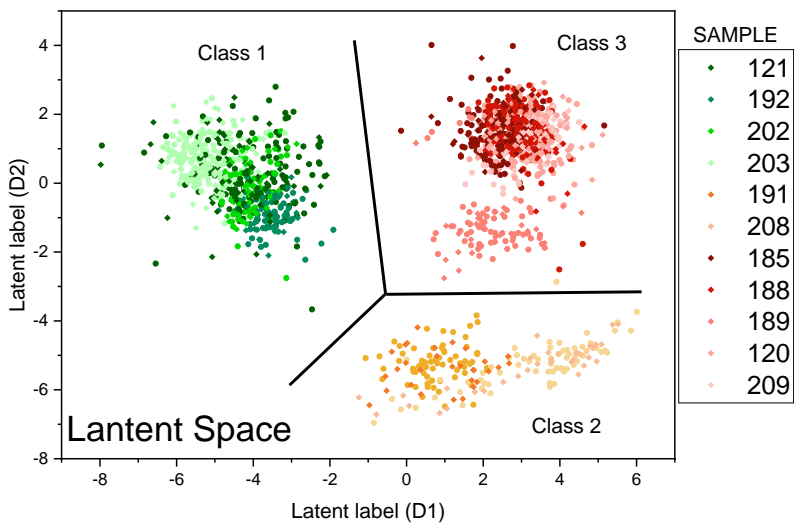
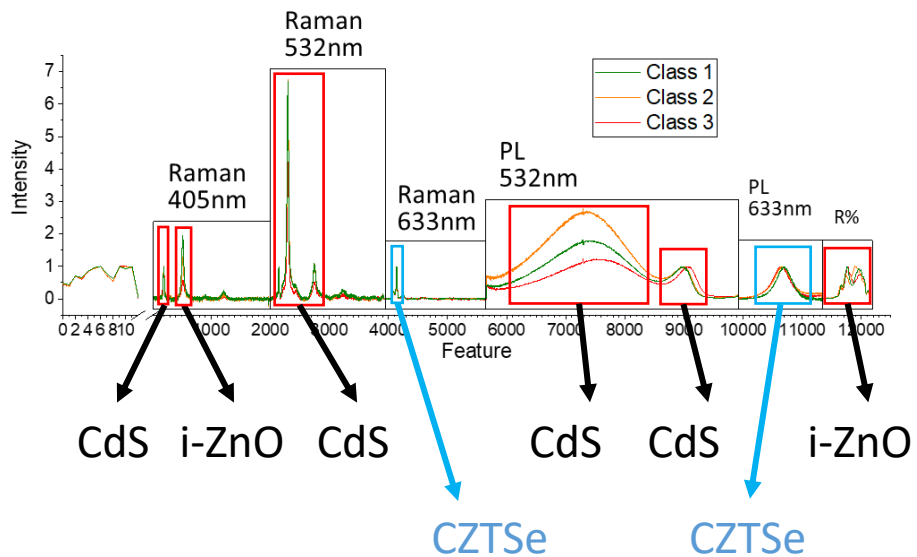
Classification	Voc	Jsc	Fluctuation origin
Class 1	Ok	Ok	
Class 2	Ok	Deviation	Deviations controlled by i-ZnO
Class 3	Deviation		Deviations controlled by CdS

i-ZnO Layer
CdS Layer



CZTSe fabrication process does not produce the fluctuations

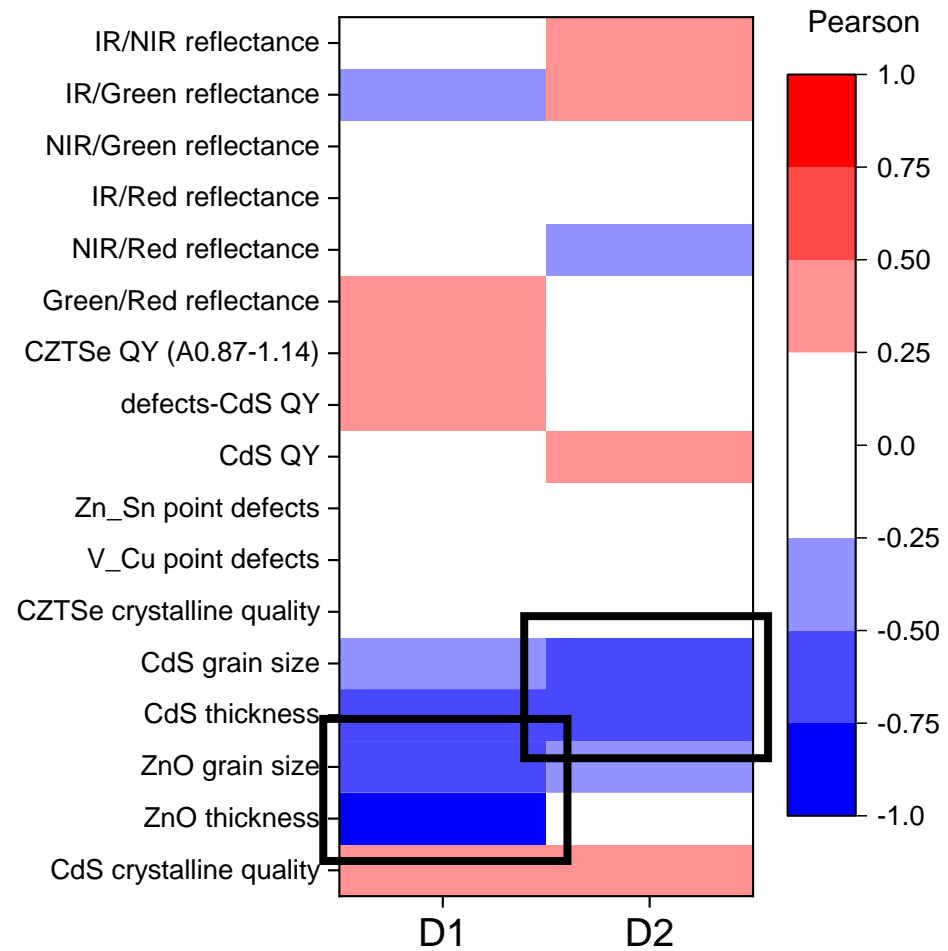
Research and knowledge generation



Permits understanding the origin and provide solutions

Combining with characterization experience...

Physico-chemical properties



Robert Fonoll –Rubio, et al
Insights into the Effects of RbF-Post-Deposition Treatments on the Absorber Surface of High Efficiency Cu(In,Ga)Se₂ Solar Cells and Development of Analytical and Machine Learning Process Monitoring Methodologies Based on Combinatorial Analysis
Adv. Energy Mater. 2022, 12, 2103163



This work has introduced:

- A robust methodology to accelerate the research on complex thin-film photovoltaic materials and devices.
- It demonstrates its validity using artificial methods in real research cases to identify the origins and causes of fluctuations during the manufacturing of a PV device.
- This universal methodology can be applied to a broad range of materials and devices, simplifying analysis in highly complex situations where conventional methods fail or are too time-consuming.
- The methodology not only speeds up the discovery process but also provides an explainable machine learning model, enhancing understanding of the technologies under study. Its ultimate goal is to equip the scientific community with a framework that promotes the integration of AI and combinatorial analysis in material and device R&D.



Enric Grau-Luque, et al
Accelerating the Development of Thin Film Photovoltaic Technologies: An Artificial Intelligence Assisted Methodology Using Spectroscopic and Optoelectronic Techniques,
Small Methods (2024) 2301573/17.

Robert Fonoll –Rubio, et al
Insights into the Effects of RbF-Post-Deposition Treatments on the Absorber Surface of High Efficiency Cu(In,Ga)Se₂ Solar Cells and Development of Analytical and Machine Learning Process Monitoring Methodologies Based on Combinatorial Analysis
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Thank you for your attention!!

Technology validation on real production lines

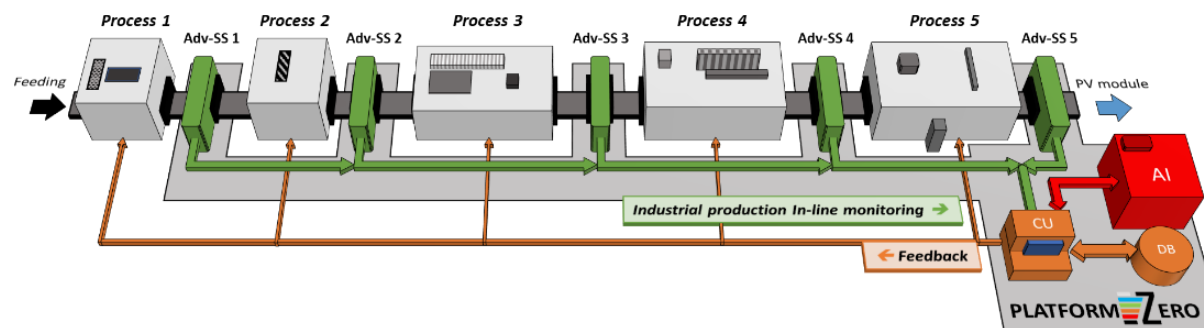


Customizable AI-based in-line process monitoring platform for achieving zero-defect manufacturing in the PV industry (Platform-ZERO)

January 2023 – December 2026



"The goal of this project is to adapt, integrate, and validate this strategy as a tool for industrial process monitoring in 2 photovoltaic companies and 2 pilot lines, with the aim of improving the quality of photovoltaic devices and reducing their environmental impact."



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<http://www.platform-zero-project.eu/>

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